

Publications by John Donovan

- [John J Donovan et al., An Improved Average Atomic Number Calculation for Estimating Backscatter and Continuum Production in Compounds, Microscopy and Microanalysis, \(2023\)](#)
- [John J Donovan and others, A New Method for Dead Time Calibration and a New Expression for Correction of WDS Intensities for Microanalysis, Microscopy and Microanalysis, \(2023\)](#)
- [Donovan, John, et al. "Quantitative WDS Compositional Mapping Using the Electron Microprobe." *The American Mineralogist* \(2021\).](#)
- [Donovan, Fellowes and McMorran, "Average Atomic Number and Electron Backscattering in Compounds", *Microsc. Microanal.* 25 \(Suppl 2\), 2019](#)
- [Donovan, Pinard and Demers, "High Speed Matrix Corrections for Quantitative X-ray Microanalysis Based on Monte Carlo Simulated K-Ratio Intensities", *Microscopy & Microanalysis*, 25, 735-742, \(2019\)](#)
- [Secondary Fluorescence effects in microbeam analysis, *Chemical Geology*, 490, 22-29, \(2018\)](#)
- [Donovan, Singer and Armstrong, "A New EPMA Method for Fast Trace Element Analysis in Simple Matrices", *American Mineralogist*, v101, p1839-1853, \(2016\)](#)
- [Donovan, et al., "High Speed Matrix and Secondary Fluorescence Corrections based on Monte Carlo Calculations" \(EMAS, 2013\)](#)
- [Llovet, et al., "Secondary fluorescence in electron probe microanalysis of couple materials", *J. Appl. Phys.*, \(2012\)](#)
- [Donovan, et al., "High Speed Matrix and Secondary Fluorescence Effects From Fundamental Parameter Monte Carlo Calculations" \(M&M, 2012\)](#)
- [Donovan, et al., "Improved electron probe microanalysis of trace elements in quartz", *American Mineralogist*, 96, 274282, 2011](#)
- [Escuder, et al., "Numerical Correction for Secondary Fluorescence Across Phase Boundaries in EPMA", 11th European Workshop on Modern Developments and Applications in Microbeam Analysis IOP Publishing IOP Conf. Series: Materials Science and Engineering 7 \(2010\)](#)

- [Phung, et al., "Determination of the Composition Ultra Thin Ni-Si Films" \(X-ray Spectrometry, 2008\)](#)
- [Meisenkothen and Donovan, "Specimen Heterogeneity Analysis: Revisted \(M&M, 2008\) \(Abstract\)](#)
- [Meisenkothen and Donovan, "Specimen Heterogeneity Analysis: Revisted \(M&M, 2008\) \(Presentation\)](#)
- [Donovan, et al., "An Iterated Blank Correction for Improved Trace Element Accuracy in EPMA" \(M&M, 2007\)](#)
- [Donovan, "Core Community Specifications for Purchasing and Acceptance of Electron Beam Instruments" \(M&M, 2005\)](#)
- [Donovan and Rowe, "Techniques for Improving Quantitative Analysis of Mineral Glasses" \(Goldschmidt, 2005\)](#)
- [Donovan, and Pingitore, "Compositional Averaging of Continuum Intensities in Multi-Element Compounds" \(M&M, 2002\)](#)
- [Donovan, et al., "Compositional Averaging of Backscatter Intensities in Compounds" \(M&M, 2003\)](#)
- [Donovan, "Compositional Averaging of Backscatter Intensities in Compounds"- Comment by Reed and Response to Reed \(M&M, 2003\)](#)
- [Donovan, et al., "A re-examination of the rare-earth-element orthophosphate standards in use for electron-probe microanalysis:, Cand. Min., 2003.](#)
- [Donovan, "Practical Considerations for Mosaic Imaging in Electron Beam Instruments" \(Scanning, 1997\)](#)
- [Donovan and Tingle, "An Improved Mean Atomic Number Background Correction for Quantitative Microanalysis" \(Jour. of Micros. Microa, 1996\)](#)
- [Donovan, et al., "An Improved Interference Correction for Trace Element Analysis" \(Microbeam Analysis, 1993\)](#)